

CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

Precision Technologies, Inc.

1740 State Route 61 Crestline, OH 44827

Fulfills the requirements of

ISO/IEC 17025:2017

In the fields of

CALIBRATION and DIMENSIONAL MEASUREMENT

This certificate is valid only when accompanied by a current scope of accreditation document. The current scope of accreditation can be verified at www.anab.org.

SD

R. Douglas Leonard Jr., VP, PILR SBU

Expiry Date: 16 April 2024 Certificate Number: L2006-1





SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

Precision Technologies, Inc.

1740 State Route 61 Crestline, OH 44827 Chris Brickner 419-683-8029

CALIBRATION AND DIMENSIONAL MEASUREMENT

Valid to: April 16,2024 Certificate Number: L2006-1

CALIBRATION

Length - Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-) 1	Reference Standard, Method, and/or Equipment
Calipers (0.000 5 resolution)	(0 to 12) in	(420 + 4.7 <i>L</i>) μin	Gage Blocks
Calipers (0.001 resolution)	(0 to 12) in	$(580 + 0.6L) \mu in$	Gage Blocks
Depth Micrometers	(0 to 12) in	$(590 + 0.5L) \mu in$	Gage Blocks
OD Micrometers	(0 to 12) in	(650 + 16.8 <i>L</i>) μin	Gage Blocks
Dial Indicators	(0 to 0.5) in	(630 + 25.1 <i>L</i>) μin	Gage Blocks
Digital Indicator	(0 to 1) in	(55 + 30.1 <i>L</i>) μin	Gage Blocks
Micrometer Standards, Length Rods	Up to 20 in	(20 + 4.7 <i>L</i>) μin	Helios w/Ref Block
Thread Plugs Major Diameter Pitch Diameter	Up to 2.4 in	134 μin 144 μin	Helios w Thread Wires
Pin Gages	Up to 1 in	20 μin	Helios
Ring Gages	Up to 4 in	(41 + 26 <i>L</i>) μin	Helios





DIMENSIONAL MEASUREMENT

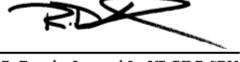
3 Dimensional

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-) 1	Reference Standard, Method, and/or Equipment
Dimensional Measurement 3D	X = (0 to 60) in Y = (0 to 125) in Z = (0 to 50) in	(380 + 39L) µin	CMM with Probe
	X = (0 to 27.5) in Y = (0 to 39.5) in Z = (0 to 20.5) in	(380 + 37L) µin	

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 (*k*=2), corresponding to a confidence level of approximately 95%.

Notes:

- 1. L = length in inches.
- 2. This scope is formatted as part of a single document including Certificate of Accreditation No. L2006-1.



R. Douglas Leonard Jr., VP, PILR SBU

